

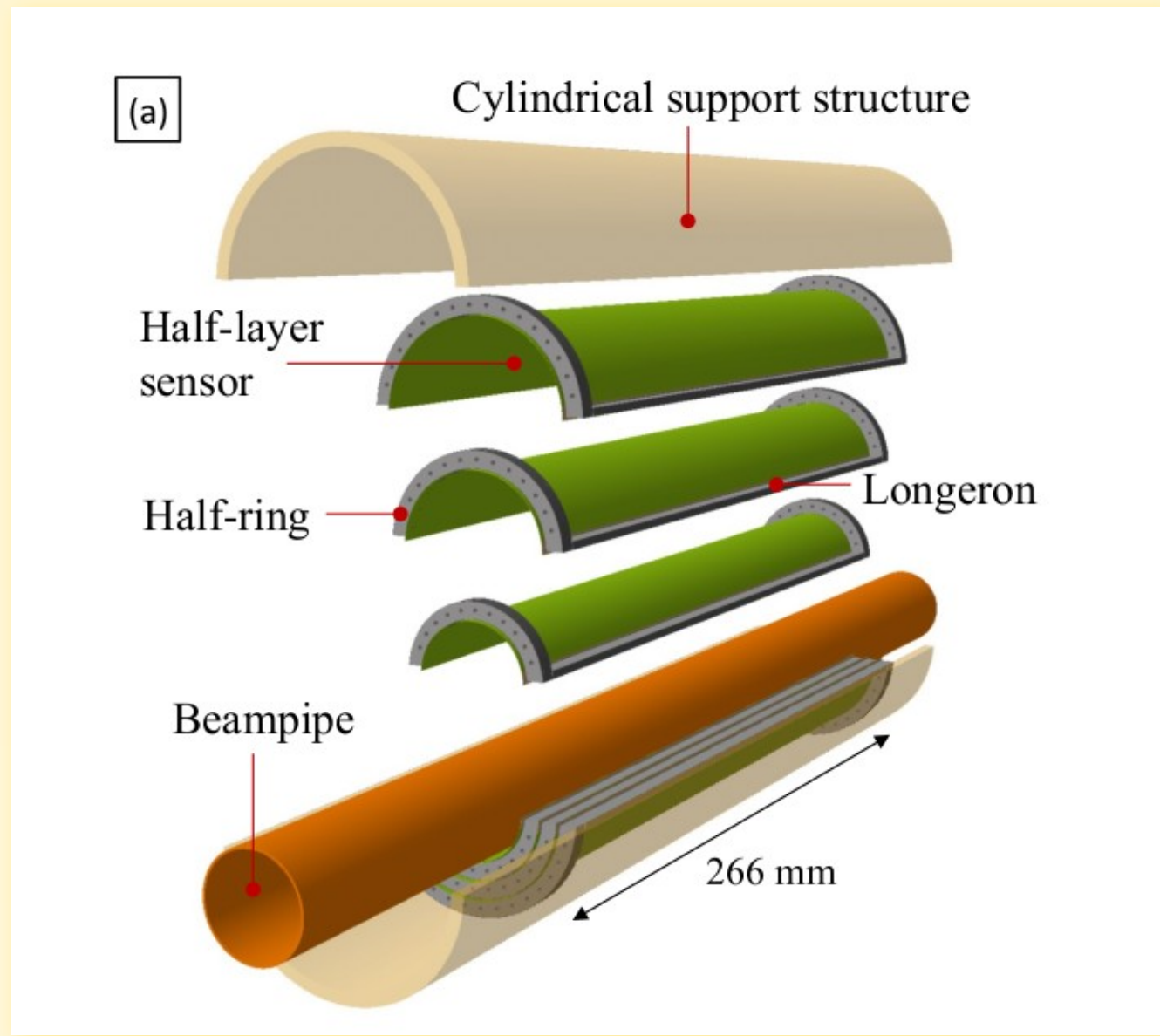
Characterisation of small scale MLR1 devices for ALICE ITS3

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on behalf of ALICE Collaboration



ALICE

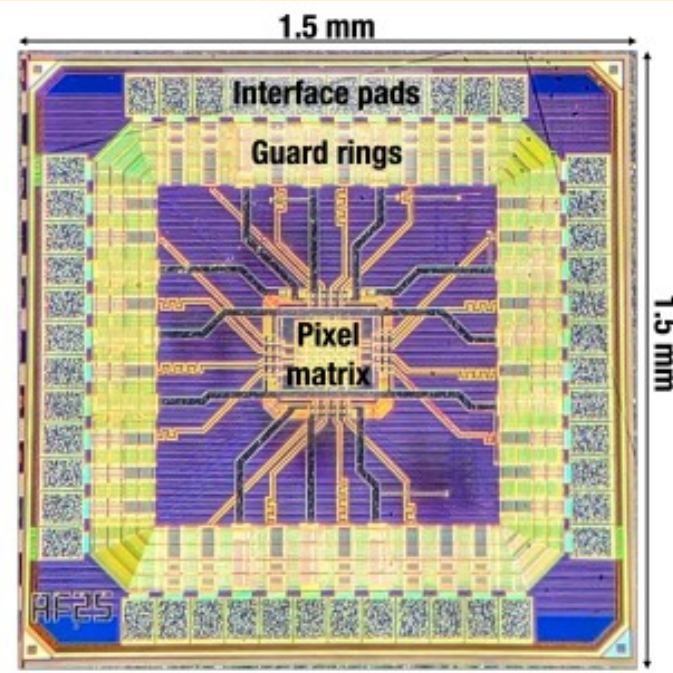
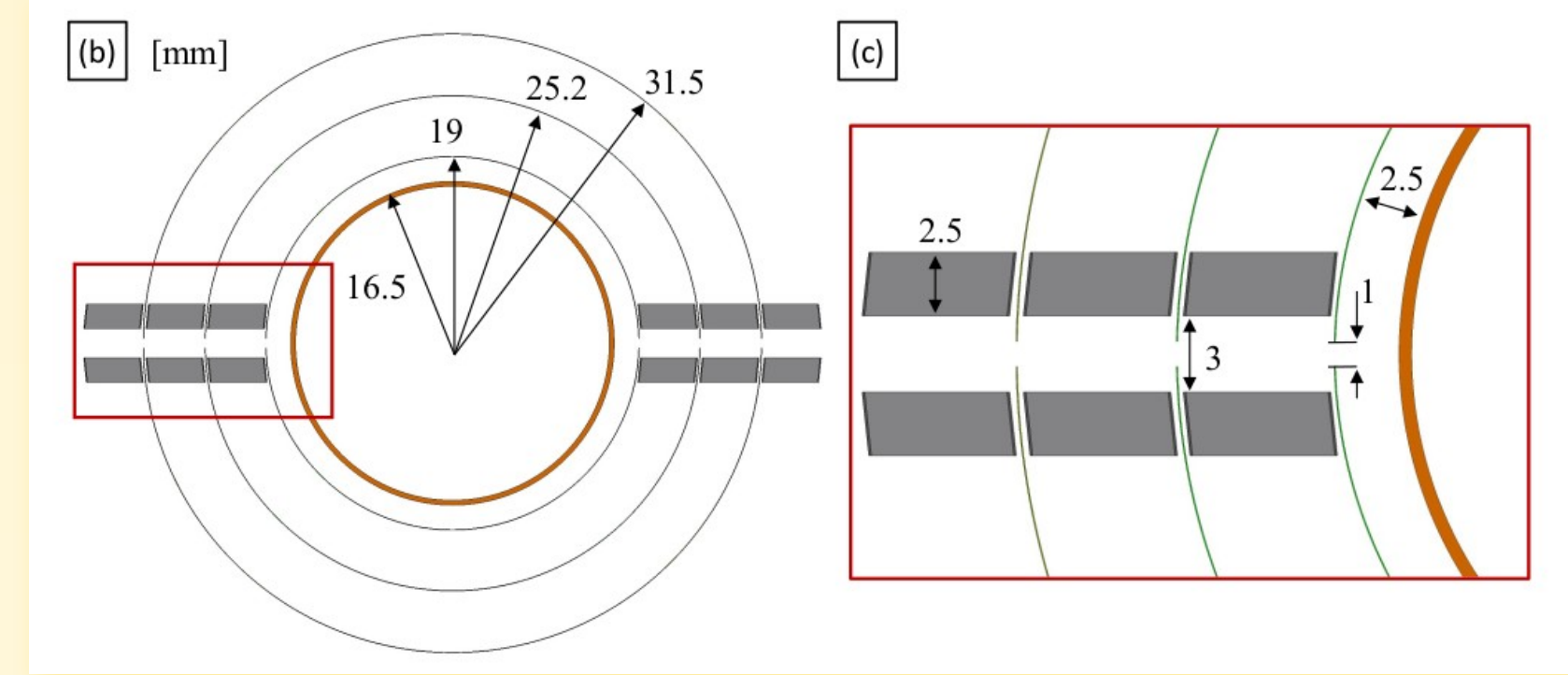
Eleventh International Workshop on Semiconductor Pixel Detectors for Particles and Imaging
(Strasbourg, 18-22 November 2024)



The Inner Tracking System (ITS) of ALICE detector, presently consisting of 7 CMOS MAPS monolithic sensors layers (ALPIDE, i.e. ALICE Pixel DEtector), is scheduled to be upgraded during Long Shutdown 3 (2026-2028). The 3 innermost layers (Inner Barrel or IB) will be replaced with 6 flexible and truly cylindrical half-barrels, that will reduce the material budget down to an average of 0.09% X_0 per layer, by removing most non-silicon contributions. ITS3 is expected to reduce systematic uncertainties on heavy-flavored (charmed, beauty), short-lived hadron yields, such as Λ_c^+ baryon ($ct = 60.4 \mu\text{m}$).

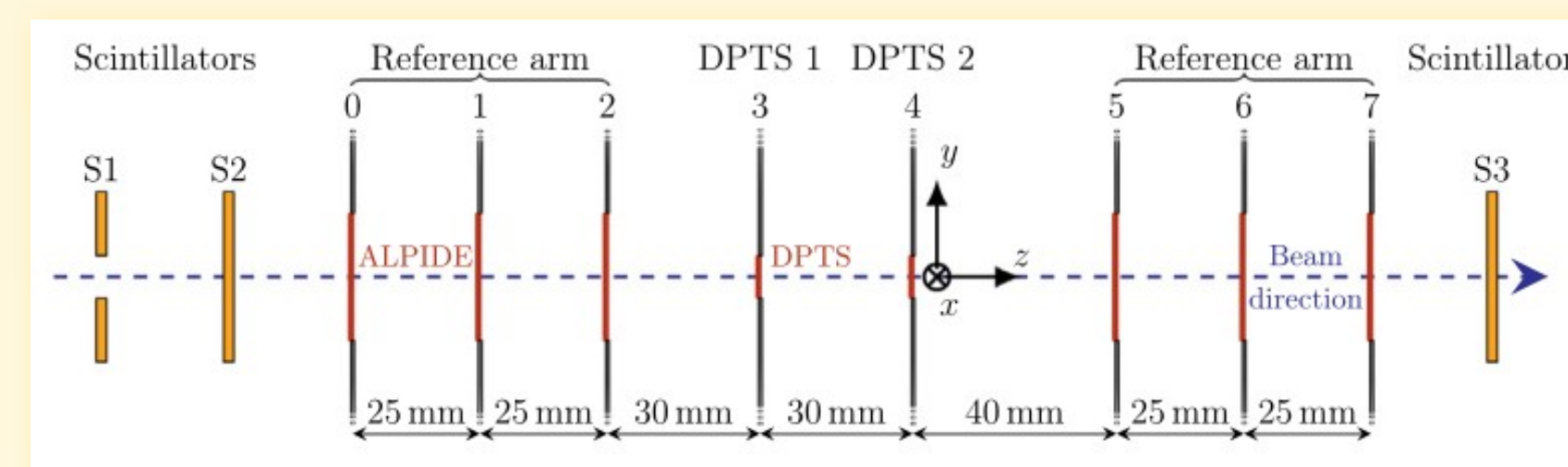
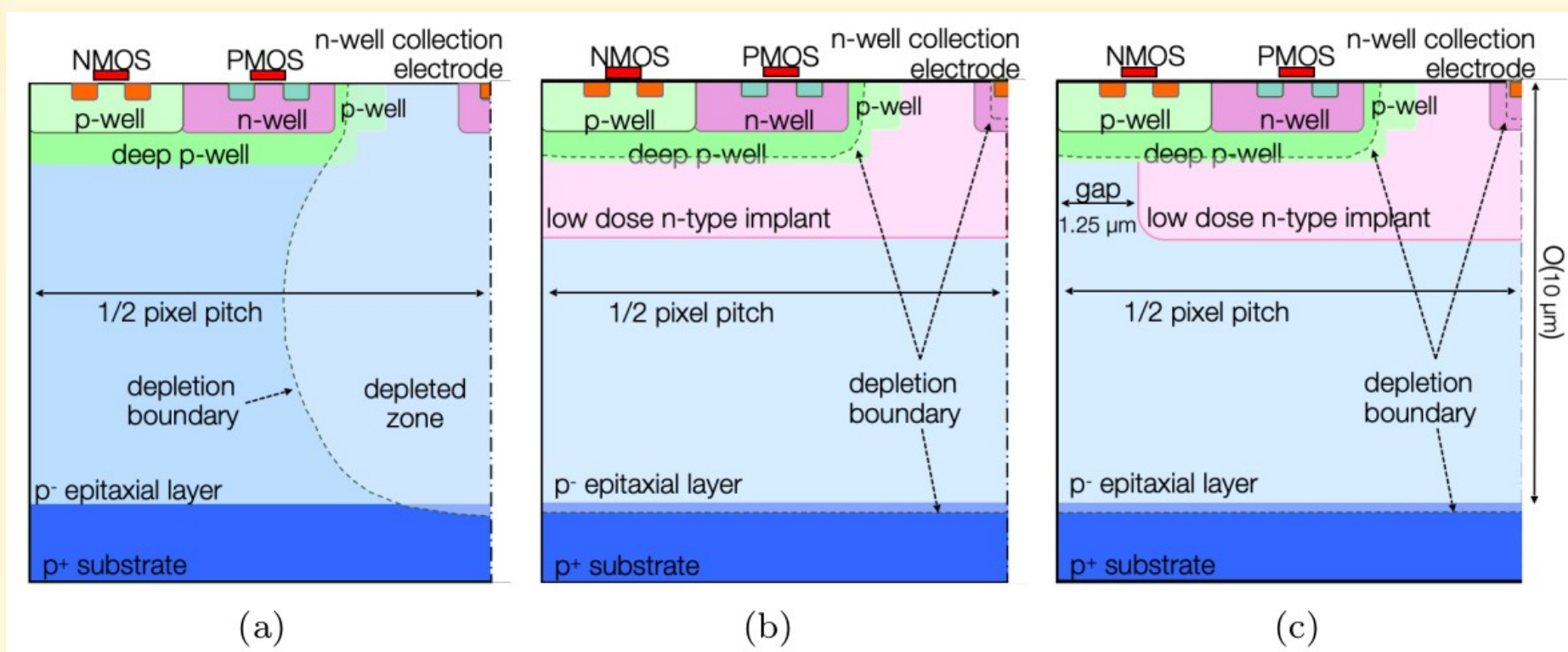
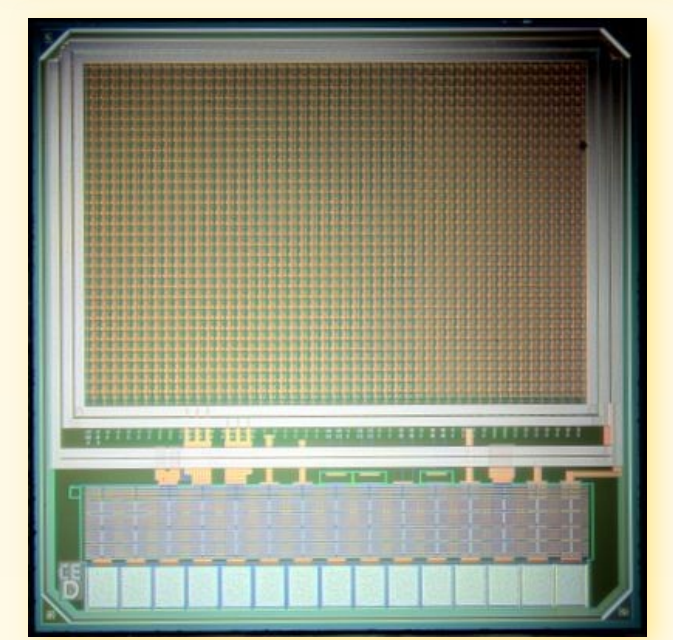
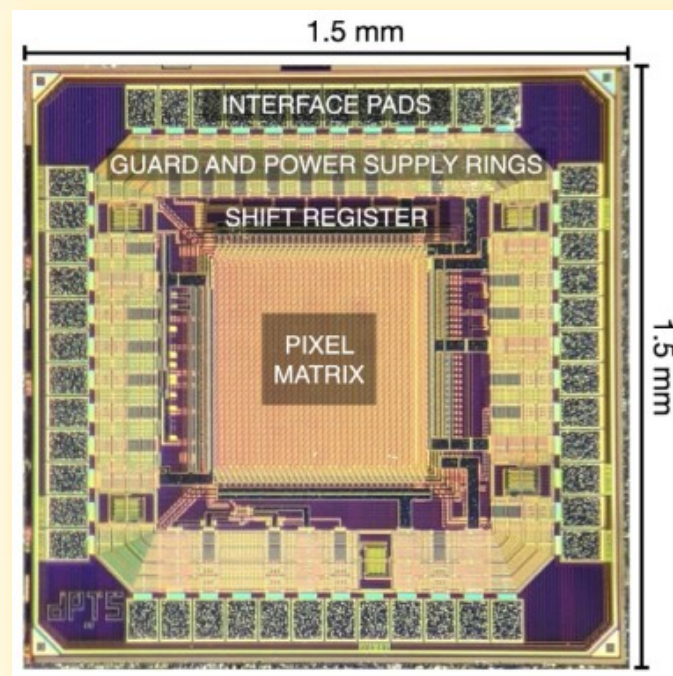
ALICE ITS3:

- 26 cm long sensitive area;
- Radius: 19 mm (L0), 25.2 (L1), 31.5 (L2);
- $20 \mu\text{m} \times 22.5 \mu\text{m}$ pixel size;
- Sensor thickness $\leq 50 \mu\text{m}/\text{layer}$;
- Pseudo-rapidity $|\eta| \leq 2.5$ (L0), 2.3 (L1), 2.0 (L2)

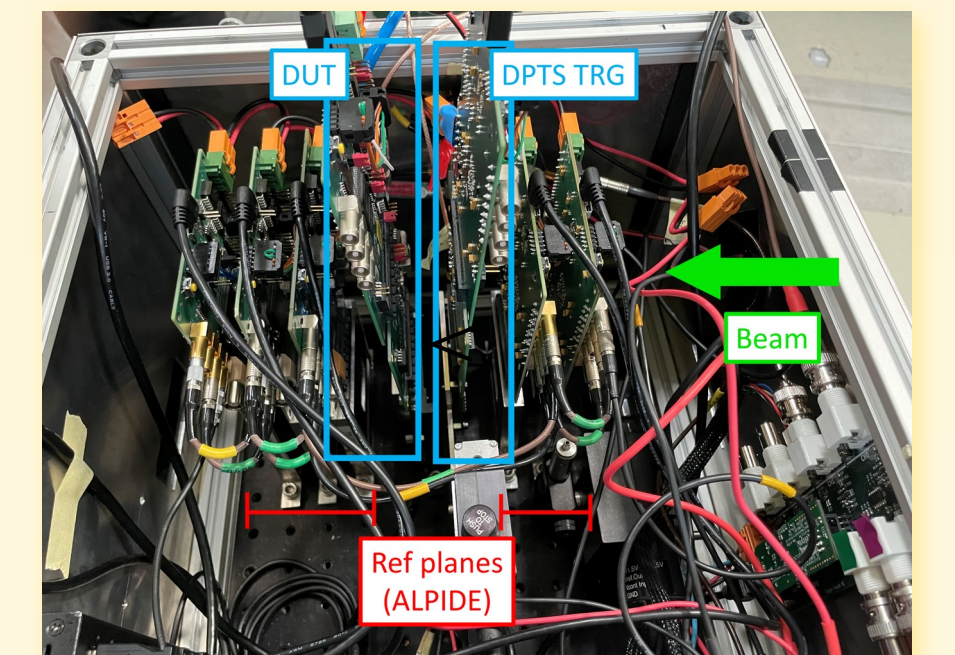


MLR1 test structures

- APTS (*top*) - Analog Pixel Test Structures
→ 6x6 pixel matrix (4x4 readout matrix): 10-25 μm , standard (a), modified (b), modified with gaps (c);
→ Source-Follower (APTS-SF) or Operational Amplifier (APTS-OA) output buffer;
- DPTS (*center*) - Digital Pixel Test Structures
→ 32x32 pixel matrix: 15 μm , modified with gaps (c);
- CE65 (*bottom*) - Circuit Exploratoire 65 nm
→ 64x32 pixel matrix: 15 μm (3 variants);
→ 48x32 pixel matrix: 25 μm (1 variant).



DPTS Testbeam @ DESY, July 2022



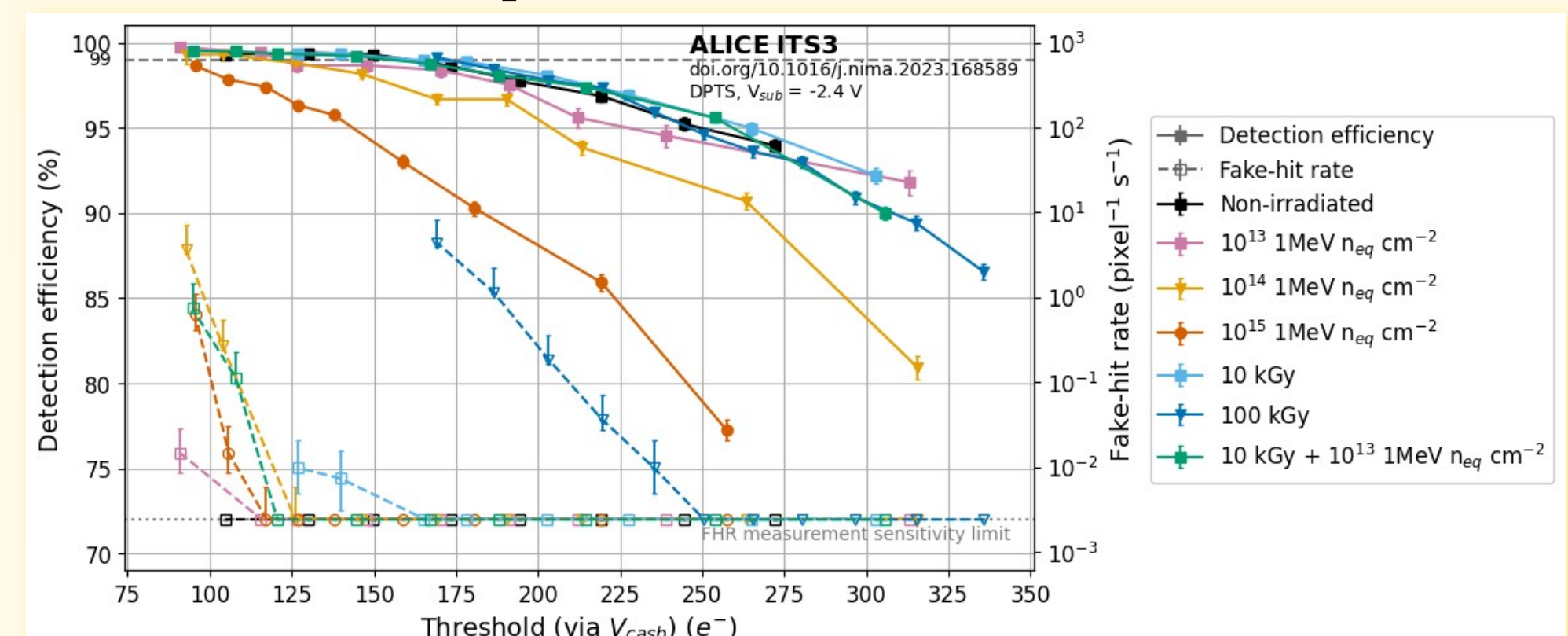
APTS and DPTS – Test beam measurements

Device Under Test (DUT): targeted with high-momentum charged particle beams, also after neutron or X-rays irradiation (JSI Ljubljana, CERN PS) at different NIEL and TID levels (APTS test beam setup shown above). Charged particle tracks were reconstructed, together with (if any) signal clusters along them.

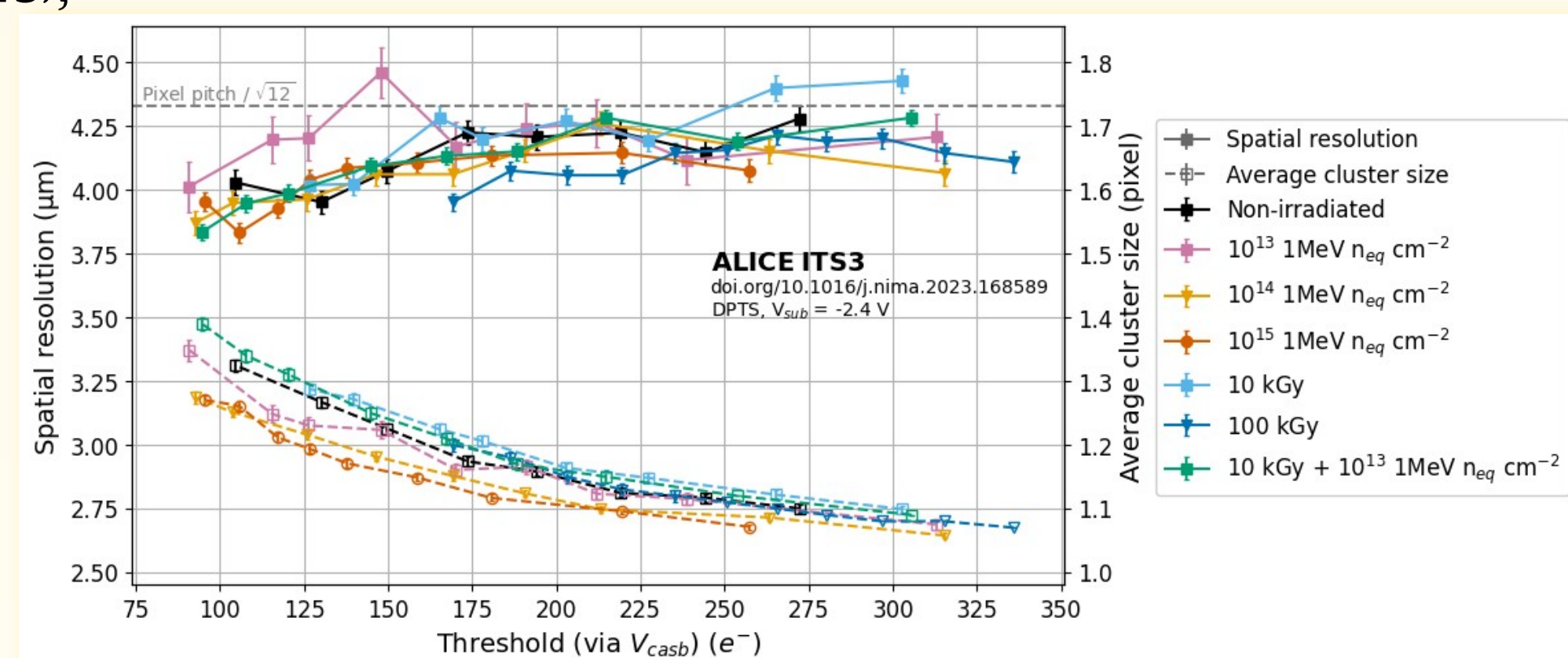
- Detection efficiency: (#tracks with signal cluster)/(#tracks);
- Spatial resolution: standard deviation of track-to-cluster distance on DUT;
- Time resolution (APTS-OA): evaluated from the distribution of time differences between DUT signal and a reference LGAD sensor signal.

Detection efficiency, spatial and timing resolution in test beam measurements

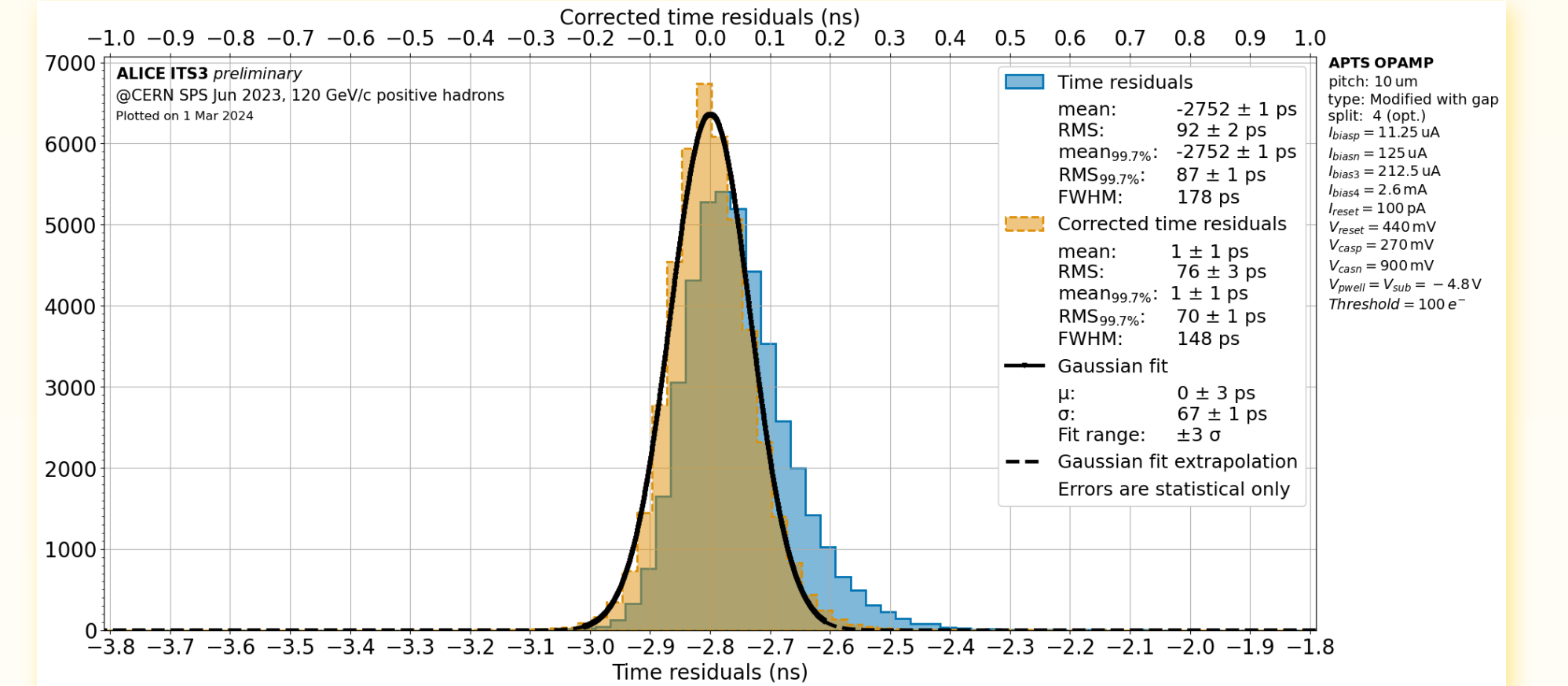
- Detection efficiency > 99% in ITS3 working conditions (10 kGy TID + 10^{13} 1 MeV $n_{\text{eq}}/\text{cm}^2$ NIEL), FHR < 0.1 hits $\text{pixel}^{-1} \text{s}^{-1}$ (DPTS);



- Spatial resolution < 5 μm for 15 μm (or smaller) pitches up to $\sim 10^{15}$ 1 MeV $n_{\text{eq}}/\text{cm}^2$ NIEL (DPTS);



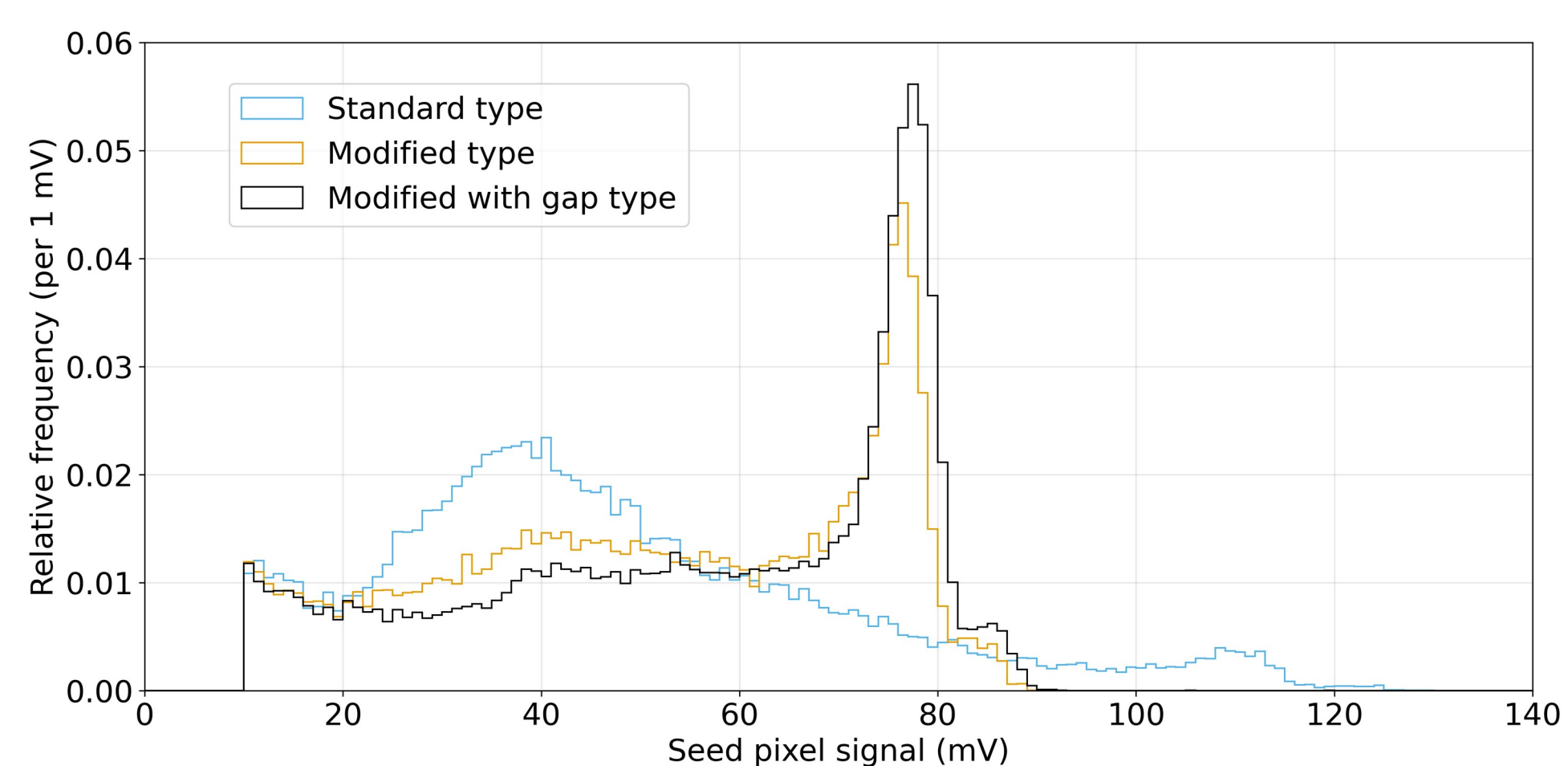
- Time resolution as good as $\sigma_t = 63 \pm 3$ ps (at a back-bias voltage $V_{\text{bb}} = -4.8$ V).



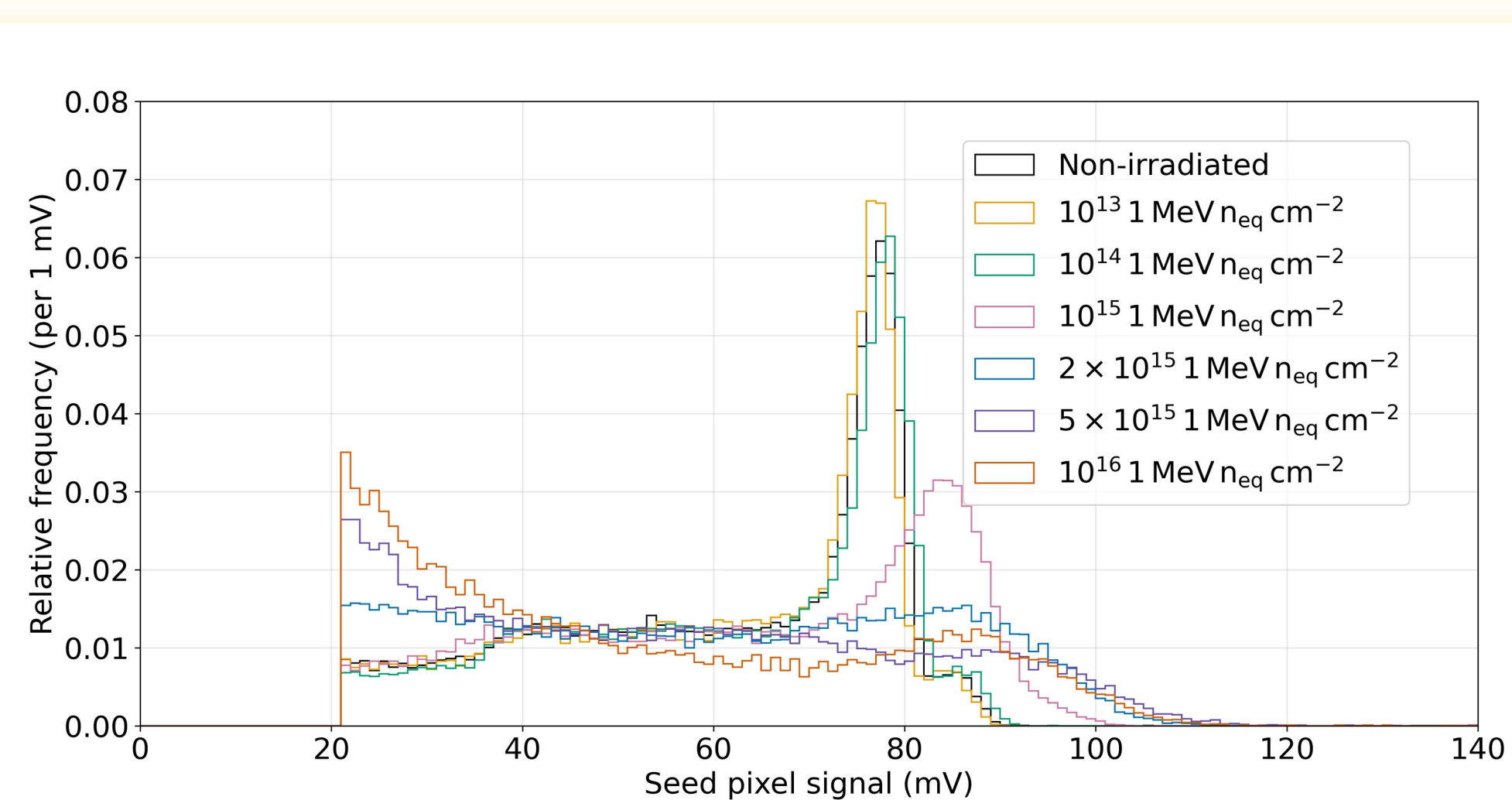
APTS-SF Tests – Laboratory measurements with ^{55}Fe source

^{55}Fe X-spectra have been acquired with chips of varying design, back-bias voltage, pixel pitch, production process (split), collection diode geometry and irradiation level (NIEL).

- ^{55}Fe - K_{α} line (5.9 keV = 1640 el.) is the reference calibration peak;
- Very small input capacitance C_{in} (no larger than 6 fF);
- Good energy resolution, improving to 6% with increasing back-bias;
- Up to $\sim 100\%$ charge collection efficiency (15 μm modified chips), even at 10^{14} 1 MeV $n_{\text{eq}}/\text{cm}^2$ NIEL (10 times larger than ITS3 working conditions);
- Small average signal cluster size (~ 1.5 pixels for modified chips).



Varying design: comparison of spectra acquired by standard, modified and modified with gap devices.



Varying NIEL level: no irradiation up to 10^{16} 1 MeV $n_{\text{eq}}/\text{cm}^2$ NIEL (modified with gap, 15 μm).

Conclusions

- Modified with gaps devices have shown high charge collection efficiency, even up to 10^{14} 1 MeV $n_{\text{eq}}/\text{cm}^2$ NIEL;
- Detection efficiency and spatial resolution tests have surpassed ITS3 expected goals: 15 μm pixel devices have shown a measured $\sim 99\%$ efficiency up to 10^{14} 1 MeV $n_{\text{eq}}/\text{cm}^2$ NIEL, spatial resolution < 5 μm . Time resolution was estimated ~ 63 ps.

• The ALICE Collab. Technical Design Report for the ALICE Inner Tracking System 3 – ITS3. A bent wafer-scale monolithic pixel detector. CERN-LHCC-2024-003, <https://cds.cern.ch/record/2890181>

• The ALICE Collab. Upgrade of the ALICE Inner Tracking System during LS3: study of physics performance. <https://cds.cern.ch/record/2868015>

• G. Aglieri Rinella et al. Characterization of analogue Monolithic Active Pixel Sensor test structures implemented in a 65 nm CMOS imaging process. NIMA 1069 (2024) 169896, DOI:10.1016/j.nima.2024.169896

• G. Aglieri Rinella et al. Digital pixel test structures implemented in a 65 nm CMOS process. NIMA 1056 (2023) 168589, DOI:10.1016/j.nima.2023.168589

• G. Aglieri Rinella et al. Time performance of Analog Pixel Test Structures with in-chip operational amplifier implemented in 65 nm CMOS imaging process. Submitted to NIMA, DOI:10.48550/arXiv.2407.18528